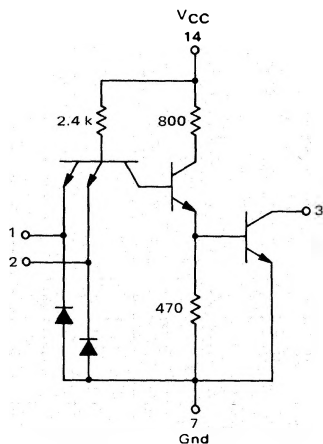


QUAD 2-INPUT "NAND" GATE
(Open Collector)

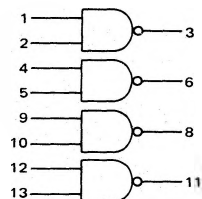
MC3100/MC3000 series

MC3104F • MC3004F
MC3104L • MC3004L,P
(54H01J) (74H01J,N)

CIRCUIT SCHEMATIC
1/4 OF CIRCUIT SHOWN



This device consists of four 2-input NAND gates with no output pull-up circuits. It can be used where the Wired-OR-function is required or for driving discrete components.



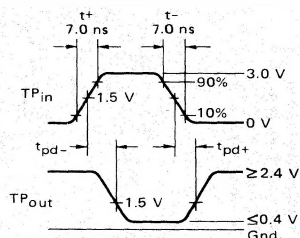
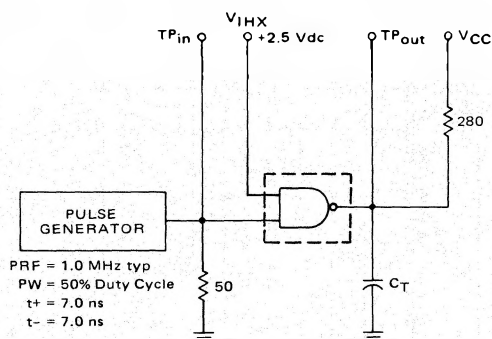
Positive Logic: $3 = \overline{1 \cdot 2}$
Negative Logic: $3 = \overline{1} + \overline{2}$

Input Loading Factor = 1
Output Loading Factor = 10
Total Power Dissipation = 88 mW typ/pkg
Propagation Delay Time = 8.0 ns typ

Pin numbers for the 54H01F/74H01F device are shown in the chart. These devices are available on special request.

DEVICE	PIN NUMBERS													
MC3104F,L/3004F,L,P	1	2	3	4	5	6	7	8	9	10	11	12	13	14
54H01F/74H01F	1	2	3	6	7	5	11	8	9	10	14	12	13	4

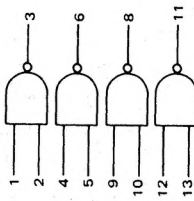
SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



$C_T = 25$ pF = total parasitic capacitance, which includes probe, wiring, and load capacitances.

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one gate. The other gates are tested in the same manner. Further, test procedures are shown for only one input of the gate under test. To complete testing, sequence through remaining inputs.



Characteristic		Symbol	Pin Under Test	MC3104 Test Limits						MC3004 Test Limits						TEST CURRENT / VOLTAGE VALUES																				
				-55°C			+25°C			+125°C			0°C			+25°C			+75°C			TEST CURRENT / VOLTAGE APPLIED TO PINS LISTED BELOW:														
				Min	Max	Unit	Min	Max	Unit	Min	Max	Unit	Min	Max	Unit	Min	Max	Unit																		
				mA														Volts																		
		I _{OL}	I _{in}	I _b	V _{IL}	V _{IH}	V _F	V _R	V _{BEH}	V _{CEX}	V _{max}	V _{CC}	V _{CCL}	V _{CCH}	V _{HX}																					
Input	Forward Current	I _F	1	-	-2.0	-	-2.0	-	-2.0	-	-2.0	-	-2.0	-	-2.0	-	-2.0	mAdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7*		
	Leakage Current	I _R	1	-	50	-	50	-	50	-	50	-	50	-	50	-	50	μAdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2,7*		
	Breakdown Voltage	BV _{in}	1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	Vdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	2,7*		
	Clamp Voltage	V _D	1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	Vdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7*		
Output	Output Voltage	V _{OL}	3	-	0.4	-	0.4	-	0.4	-	0.4	-	0.4	-	0.4	-	0.4	Vdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7*	
	Output Leakage Current	I _{CEX}	3	-	250	-	250	-	250	-	250	-	250	-	250	-	250	μAdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7*	
Power Requirements (Total Device)		I _{max}	14	-	-	-	25	-	-	-	-	-	25	-	-	-	-	mAdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	1, 2, 4, 5, 7, 9, 10, 12, 13	
Power Supply Drain		I _{PPH}	14	-	36	-	36	-	36	-	36	-	36	-	36	-	36	mAdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7
Power Supply Drain		I _{PDL}	14	-	10	-	10	-	10	-	10	-	10	-	10	-	10	mAdc	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	1, 2, 4, 5, 7, 9, 10, 12, 13
Switching Parameters		I _{pd-}	1, 3	-	-	-	14	-	-	-	-	-	14	-	-	-	-	ns	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7*	
Turn-Off Delay		I _{pd+}	1, 3	-	-	-	20	-	-	-	-	-	20	-	-	-	-	ns	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	7*	

* Since this is an inverting gate, power drain is minimized by grounding the inputs to gates not under test.